

**Notice of References Cited**

Application/Control No.

10/587,617

Applicant(s)/Patent Under  
Reexamination  
LEIGRAF ET AL.

Examiner

Binh X. Tran

Art Unit

1792

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0178165	09-2003	Bobsein et al.	162/135
*	B	US-2002/0117277	08-2002	Johnson et al.	162/124
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 02103109 A1	12-2002	World Intellect	ALEKSANDAR T et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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